

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/535,423	OKAHARA ET AL.
Examiner	Art Unit	
	EDMUND H. LEE	1791

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
264/328	7,255,250,328.8 ,328.11	8/28/2010	EHL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**